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# RF Exposure Evaluation Report

**Report No.:** CQASZ20200500394E-02

**Applicant:** TYLT, inc.

**Address of Applicant:** 685 Cochran St. Suite 200, Simi Valley, California 93065, United States

**Equipment Under Test (EUT):**

**Product:** Wireless Charger

**Model No.:** QICRSTBK-T, QICRSTW-T, 4347N, 4348N

**Test Model No.:** QICRSTBK-T

**Brand Name:** N/A

**FCC ID:** 2AOAF-220

**Standards:** 47 CFR Part 1.1307

47 CFR Part 1.1310

KDB 680106 D01 RF Exposure Wireless Charging Base App v03

**Date of Receipt:** 2020-05-15

**Date of Test:** 2020-05-15 to 2020-05-22

**Date of Issue:** 2020-05-22

**Test Result :** PASS\*

\*In the configuration tested, the EUT complied with the standards specified above

**Tested By:**

Tom Chen.

(Tom Chen)

**Reviewed By:**

Sheek, Luo

(Sheek Luo)

**Approved By:**

Jack Ai.

( Jack Ai)



## 1 Version

### Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20200500394E-02	Rev.01	Initial report	2020-05-22

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### 3 General Information

#### 3.1 Client Information

Applicant:	TYLT, inc.
Address of Applicant:	685 Cochran St. Suite 200, Simi Valley, California 93065, United States
Manufacturer:	TYLT, inc.
Address of Manufacturer:	685 Cochran St. Suite 200, Simi Valley, California 93065, United States
Factory:	DONGGUAN KINTEC DIGITAL TECHNOLOGY CO.,LIMITED
Address of Factory:	8F, JINYE BUILDING, NO.306, CHANGQING SOUTH ROAD, CHANG'AN, DONGGUANG CITY, GUANGDONG, CHINA

#### 3.2 General Description of EUT

Product Name:	Wireless Charger
Model No.:	QICRSTBK-T, QICRSTW-T, 4347N, 4348N
Test Model No.:	QICRSTBK-T
Brand Name:	N/A
Hardware Version:	M05-S361-310
Software Version:	0x495356
Equipment Category	Non-ISM frequency
Operation Frequency range	110-205kHz
Modulation Type:	Induction
Antenna Type:	Induction coil
Antenna Gain:	0dBi
EUT Power Supply:	Input: 5V 2A, 9V 1.8A Output: 10W(Max)

Note:

1. In section 15.31(m), regards to the operating frequency range less 1 MHz.
2. Model No.: QICRSTBK-T, QICRSTW-T, 4347N, 4348N

Only the model QICRSTBK-T was tested, since the electrical circuit design, layout, components used and internal wiring were identical for the above models, with difference being color of appearance and model name.

### 3.3 Test Environment

<b>Operating Environment:</b>	
Temperature:	25.8°C
Humidity:	52 % RH
Atmospheric Pressure:	1009mbar
<b>Test Mode:</b>	
Mode a:	Wireless charging Mode at 9V (Full load)
Mode b:	Wireless charging Mode at 9V (half load)
Mode c:	Wireless charging Mode at 9V (Null load)
Mode d:	Wireless charging Mode at 5V (Full load)
Mode e:	Wireless charging Mode at 5V (half load)
Mode f:	Wireless charging Mode at 5V (Null load)

### 3.4 Description of Support Units

The EUT has been tested with associated equipment below.

#### 1) Support equipment

<b>Description</b>	<b>Manufacturer</b>	<b>Model No.</b>	<b>Certification</b>	<b>Supplied by</b>
Adapter	HUAWEI	LPL-C010050200Z	DOC	CQA
Wireless electronic Load	-	-	-	CQA

#### 2) Cable

<b>Cable No.</b>	<b>Description</b>	<b>Manufacturer</b>	<b>Cable Type/Length</b>	<b>Supplied by</b>
/	/	/	/	/

### 3.5 Test Location

**Shenzhen Huaxia Testing Technology Co., Ltd,**

1F., Block A of Tongsheng Technology Building, Huahui Road, Dalang Street, Longhua District, Shenzhen, China

### 3.6 Test Facility

- **A2LA (Certificate No. 4742.01)**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 4742.01.

- **FCC Registration No.: 522263**

Shenzhen Huaxia Testing Technology Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.:522263

### 3.7 Equipment List

Test Equipment	Manufacturer	Model No.	Instrument No.	Calibration Date	Calibration Due Date
Broadband Field Meter	Narda Safety Test Solutions GmbH	NBM-520	SB9873	2019/10/18	2020/10/17
Magnetic field probe	HIOKI	3470	SB9058/04	2019/12/14	2020/12/13

## 4 RF Exposure Evaluation

### 4.1 RF Exposure Compliance Requirement

#### 4.1.1 Limits

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in part1.1307(b)

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm <sup>2</sup> )	Averaging time (minutes)
<b>(A) Limits for Occupational/Controlled Exposures</b>				
0.3–3.0 .....	614	1.63	*(100)	6
3.0–30 .....	1842/f	4.89/f	*(900/f <sup>2</sup> )	6
30–300 .....	61.4	0.163	1.0	6
300–1500 .....	.....	.....	f/300	6
1500–100,000 .....	.....	.....	5	6
<b>(B) Limits for General Population/Uncontrolled Exposure</b>				
0.3–1.34 .....	614	1.63	*(100)	30
1.34–30 .....	824/f	2.19/f	*(180/f <sup>2</sup> )	30
30–300 .....	27.5	0.073	0.2	30
300–1500 .....	.....	.....	f/1500	30
1500–100,000 .....	.....	.....	1.0	30

Note 1: f = frequency in MHz ; \*Plane-wave equivalent power density

Note 2: For the applicable limit, see FCC 1.1310, 680106 D01 RF Exposure Wireless Charging Apps v03

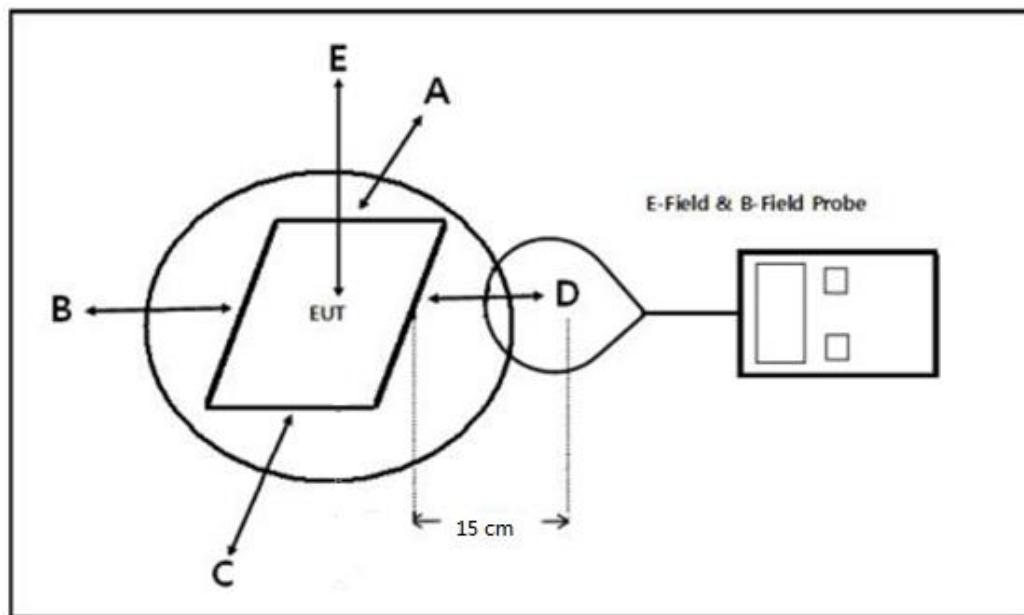
Note 3: Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. A KDB inquiry is required to determine the applicable exposure limits below 100 kHz.

Note 4: The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit .

#### 4.1.2 Test Procedure

For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 20 cm(Top) and 15cm(Edge). E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 20 cm(Top) and 15cm(Edge) measured from the center of the probe(s) to the edge of the device.

#### 4.1.3 Test Setup



Note: Position A: Front of EUT; Position B: Left of EUT; Position C: back of EUT; Position D: Right of EUT; Position E: Top of EUT(20 cm measure distance);

#### 4.1.4 Test Results

The EUT does comply with item 5 KDB680106 D01 v03.

(1) Power transfer frequency is less than 1 MHz.  
(Conform)

(2) Output power from each primary coil is less than or equal to 15 watts.  
(Conform)

(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.  
(Conform)

(4) Client device is placed directly in contact with the transmitter.  
(Conform)

(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).  
(Conform)

(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.  
(Conform)

Test condition: Mode a

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	1.15	0.98	0.65	0.73	1.08	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.23	0.44	0.37	0.46	0.38	1.63

Test condition: Mode b

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	0.96	0.73	0.57	0.60	0.91	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.18	0.33	0.26	0.31	0.27	1.63

Test condition: Mode c

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	0.94	0.81	0.46	0.34	0.69	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.14	0.23	0.21	0.27	0.15	1.63

Test condition: Mode d

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	0.86	0.74	0.43	0.38	0.75	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.16	0.27	0.12	0.24	0.10	1.63

Test condition: Mode e

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	0.83	0.63	0.41	0.49	0.84	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.10	0.29	0.14	0.17	0.13	1.63

Test condition: Mode f

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
127kHz	0.80	0.57	0.43	0.31	0.78	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
127kHz	0.13	0.15	0.25	0.14	0.11	1.63

## APPENDIX A: PHOTOGRAPHS OF TEST SETUP

Test Model No.: QICRSTBK-T



----END OF REPORT----